

In this work, we have added a temperature controller to an apparatus for measuring Pockels effect, which comprises of an integrated circuit and a Peltier element. Then the course of the electric field was measured in the sample of high resistance CdTe, a suitable detector on the high-energy radiation, depending on the voltage and temperature of the sample. Also the charge distribution in the sample was determined depending on time after the voltage and sample's temperature were reached. Finally, the activation energies of deep levels were determined, which are responsible for the polarization.